Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

243895US0DIV

SERIAL NO.

10/681,205

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Syozo KOBAYASHI, et al.

FILING DATE

October 9, 2003

GROUP

1624

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ZT	AA	6,525,042	02-25-03	KOBAYASHI et al.	514	212.03	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	


☐ Additional References sheet(s) attached

Examiner

Date Considered 10 JANUARY 2005

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243895US0DIV		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Syozo KOBAYASHI, et al.			
				FILING DATE Herewith		GROUP 1624	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ZT	AA	5,654,305	8/5/97	G.S. Sheppard, et al.	514	253	
ZT	AB	5,489,583	2/6/96	H. Mack, et al.	514	183	
	AC						
	AD						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
ZT	AE	4-342579	11/30/92	JAPAN			
ZT	AF	57-040474	3/6/82	JAPAN			
ZT	AG	3-258763	11/19/91	JAPAN			
ZT	AH	2-184673	7/19/90	JAPAN			
ZT	AI	1-316383	12/21/89	JAPAN			
ZT	AJ	58-049366	3/23/83	JAPAN			
ZT	AK	WO 98/40679	12/19/96	WIPO			
ZT	AL	WO 96/10022	4/4/96	WIPO			
ZT	AM	WO 98/21188	5/22/98	WIPO			
ZT	AN	WO 97/29104	8/14/97	WIPO			
ZT	AO	WO 98/25611	6/18/98	WIPO			
ZT	AP	WO 98/24784	6/11/98	WIPO			
ZT	AQ	WO 96/33196	10/24/96	WIPO			
ZT	AR	WO 97/28141	8/7/97	WIPO (with English Abstract)			
ZT	AS	WO 97/28139	8/7/97	WIPO (with English Abstract)			
ZT	AT	WO 97/03963	2/6/97	WIPO (with English Abstract)			
ZT	AU	WO 98/06705	2/19/98	WIPO			
ZT	AV	WO 96/41173	12/19/96	WIPO			
ZT	AW	WO 99/16747	4/8/99	WIPO (with English Abstract)			
ZT	AX	WO 99/40075	8/12/99	WIPO (with English Abstract)			
ZT	AY	WO 99/37304	7/29/99	WIPO			
ZT	AZ	WO 99/33805	7/8/99	WIPO (with English Abstract)			
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<div style="display: flex; justify-content: space-between; align-items: flex-end;"> <div style="width: 40%;"> Examiner </div> <div style="width: 50%; text-align: right;"> <input type="checkbox"/> Additional References sheet(s) attached </div> </div>					Date Considered 11 JANUARY 2005		

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AAA						
	AAB						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
ZT	AAC	WO 99/31092	8/24/99	WIPO (with English Abstract)			
ZT	AAD	WO 99/16751	4/8/99	WIPO (with English Abstract)			
ZT	AAE	WO 98/54164	12/3/98	WIPO			
ZT	AAF	WO 99/26932	6/3/99	WIPO			
ZT	AAG	WO 98/47876	10/29/98	WIPO			
ZT	AAH	WO 99/06367	2/11/99	WIPO			
ZT	AAI	WO 99/01434	1/14/99	WIPO			
ZT	AAJ	WO 99/57099	11/11/99	WIPO			
ZT	AAK	WO 99/57112	11/11/99	WIPO			
ZT	AAL	WO 97/06802	2/27/97	WIPO			
	AAM						
	AAN						
	AAO						
	AAP						
	AAQ						
	AAR						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AAS						
	AAT						
	AAU						
	AAV						<input type="checkbox"/> Additional References sheet(s) attached
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